

## Title (en)

Coated cutting tool

## Title (de)

Beschichtetes Schneidewerkzeug

## Title (fr)

Outil de coupe revêtu

## Publication

**EP 2818573 B1 20160203 (EN)**

## Application

**EP 14174143 A 20140626**

## Priority

- EP 13174011 A 20130627
- EP 14174143 A 20140626

## Abstract (en)

[origin: EP2818573A1] A coated cutting tool comprising substrate and a coating, wherein the coating comprises a layer of MTCVD TiCN, and a layer of  $\pm$ - Al 2 O 3 , wherein the  $\pm$ - Al 2 O 3 layer exhibits an X-ray diffraction pattern, as measured using CuK $\alpha$  radiation, wherein the (hkl) reflections used are (012), (104), (110), (113), (116), (300), (214) and (0 0 12), and wherein TC(0 0 12) is higher than 5 and a full width half maximum (FWHM) of a rocking curve peak of the (0 0 12) plane of the  $\pm$ - Al 2 O 3 is lower than 30°.

## IPC 8 full level

**C23C 14/08** (2006.01); **B23B 27/14** (2006.01); **C23C 16/02** (2006.01); **C23C 16/36** (2006.01); **C23C 16/40** (2006.01); **C23C 16/56** (2006.01); **C23C 30/00** (2006.01)

## CPC (source: BR CN EP KR RU US)

**B23B 27/14** (2013.01 - RU); **B23B 27/148** (2013.01 - BR KR US); **C23C 14/06** (2013.01 - BR); **C23C 14/081** (2013.01 - BR); **C23C 16/0254** (2013.01 - CN EP KR US); **C23C 16/0272** (2013.01 - BR CN EP KR US); **C23C 16/36** (2013.01 - CN EP KR RU US); **C23C 16/40** (2013.01 - RU); **C23C 16/403** (2013.01 - BR CN EP KR US); **C23C 16/44** (2013.01 - RU); **C23C 16/56** (2013.01 - BR CN EP KR US); **C23C 30/00** (2013.01 - BR); **C23C 30/005** (2013.01 - CN EP KR US); **B23B 2200/00** (2013.01 - US); **B23B 2224/04** (2013.01 - KR US); **B23B 2224/32** (2013.01 - KR US); **Y10T 407/27** (2015.01 - EP US)

## Citation (opposition)

Opponent : Iscar Ltd

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## Designated contracting state (EPC)

AL AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO RS SE SI SK SM TR

## DOCDB simple family (publication)

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## DOCDB simple family (application)

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